

Graph Partition based Path Selection for Testing of Small Delay Defects

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Outline

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- Critical path graph
- Graph partition based path selection
 - Cut-node partition
 - Independent Path Set Partition
- Experimental results
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Introduction

- Continuous shrinking of device feature size increases the following effects:

- Process Variation
- Power Noise
- Crosstalk

- Path Correlations

- Share common gates and wires
- Spatial correlations

- Purpose: find a path set S ,

$$probability(circuit_delay > clk \mid \forall p \in S, delay_p < clk) \approx 0$$

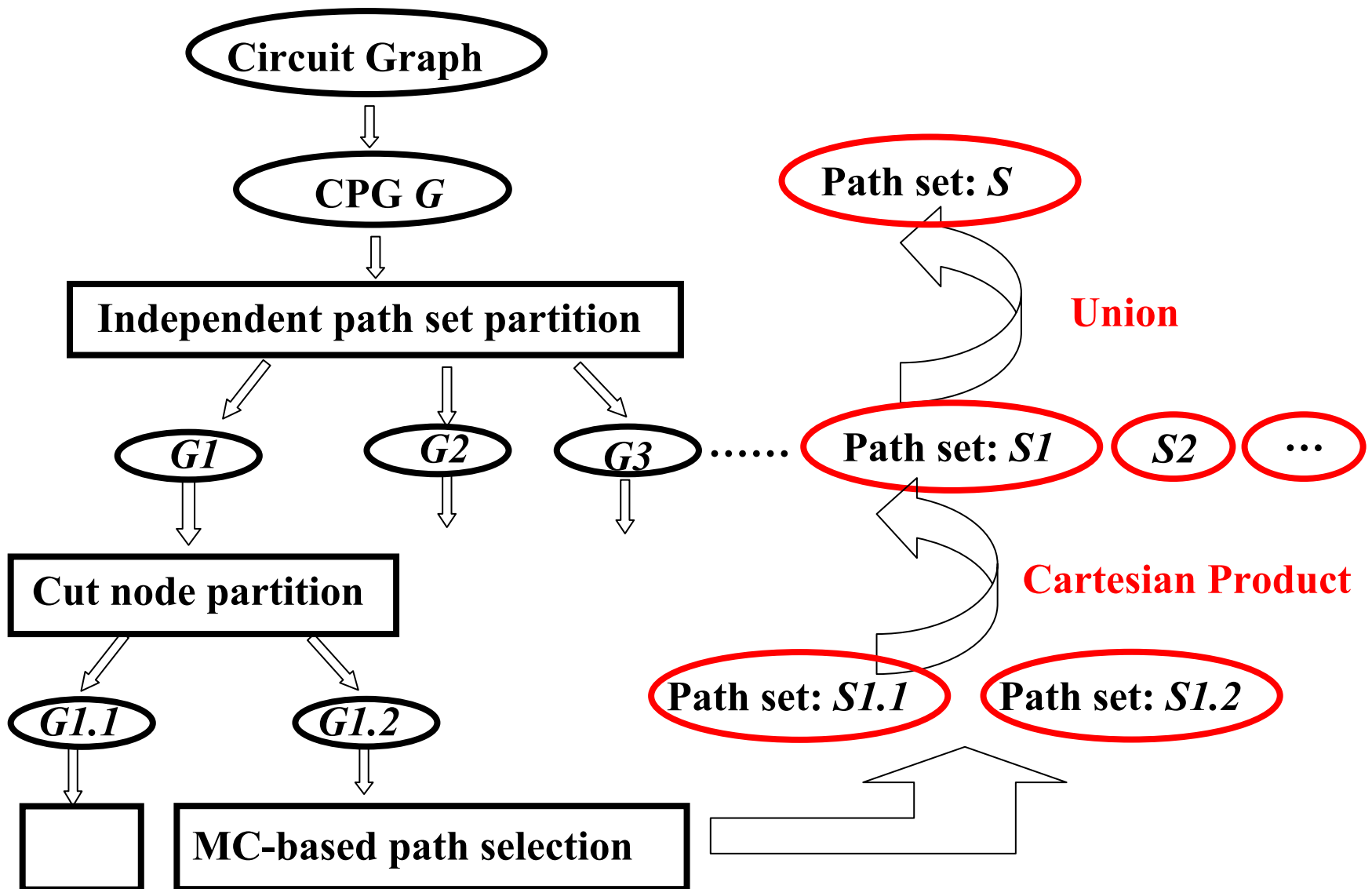
Motivation

- Monte Carlo simulation based path selection
 - A candidate critical path set is generated first
 - Circuit sample are generated for path selection
- Computing time is propositional to the number of candidate critical paths
 - Very inefficient for some circuits with large number of candidate critical paths

Our contribution

- Graph Partition based path selection
 - CPG: Critical Path Graph
 - sub graph containing all candidate critical paths
 - Two graph partition approaches for CPG
 - Cut-node partition
 - Independent path set partition
 - Two operations for test path set generation
 - Cartesian product operation
 - Union operation
- Square root level of computing complexity

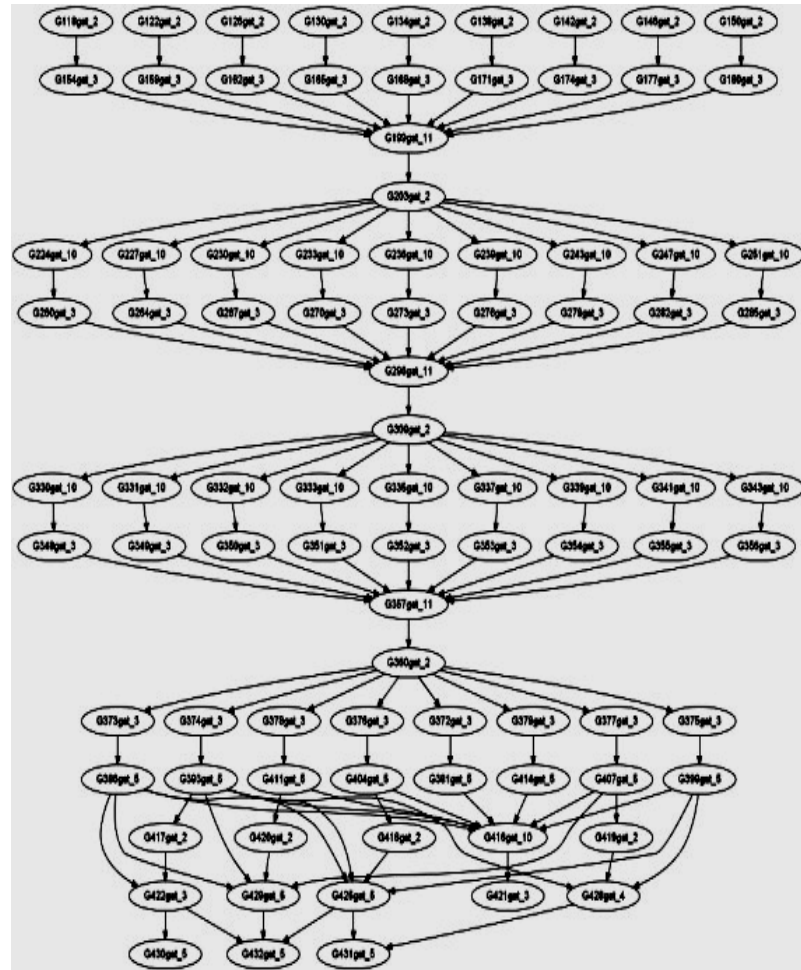
Overflow of our approach



Critical Path Graph

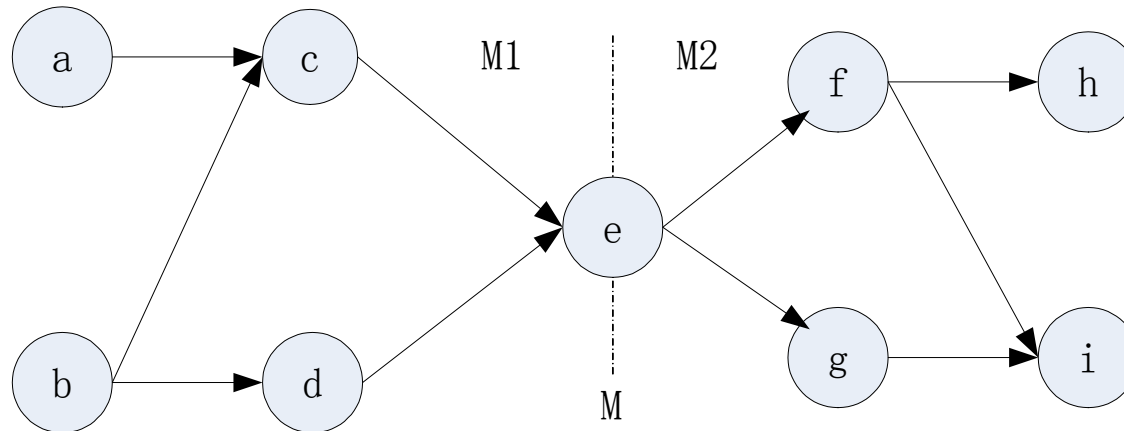
- A path is defined critical if it has certain probability longer than reference clock T

- *CPG (Critical path graph)* contains all critical paths



CPG of C432 from ISCAS85

Cut Node Partition based path selection

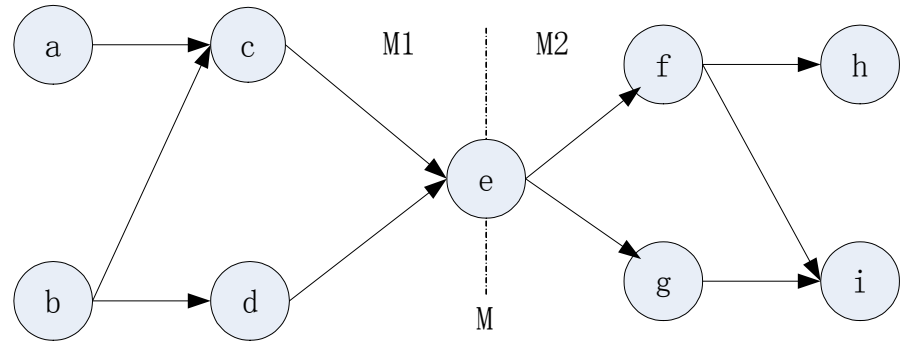


$S1$: A path set of $M1$ that can capture the worst delay situation of $M1$ with a high probability,

$S2$: A path set of $M2$ that can capture the worst delay situation of $M2$ with a high probability,

$S=S1*S2$: A path set of M that can capture the worst delay situation of M with a high probability,

Theoretical analysis



- **Definition:**

$$CL(S_1) = \text{Min}\{\text{prob}(d_{P_1} + d_{P_2} < clk \mid d_{S_1} + d_{P_2} < clk) \mid P_1 \in R_{M_1}, P_2 \in R_{M_2}\} \quad (1)$$

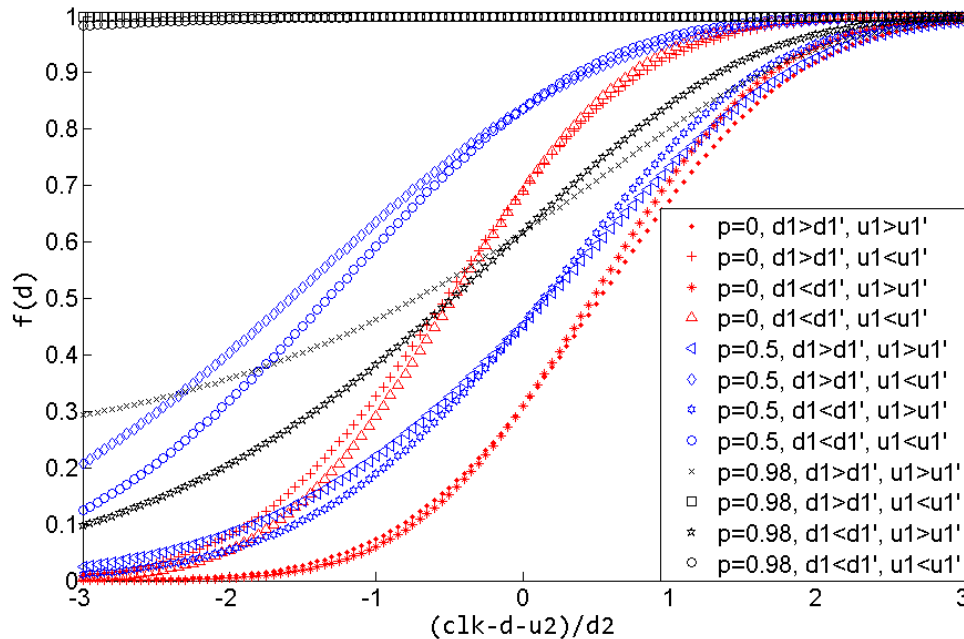
$$CL(S_2) = \text{Min}\{\text{prob}(d_{P_1} + d_{P_2} < clk \mid d_{P_1} + d_{S_2} < clk) \mid P_1 \in R_{M_1}, P_2 \in R_{M_2}\} \quad (2)$$

$$CL(S) = \text{Min}\{\text{prob}(d_P < clk \mid d_S < clk) \mid P \in R_M\} \quad (3)$$

- $CL(S_1)$ and $CL(S_2)$ give the confidence level how the character path set S_1 and S_2 can capture the delay character of M_1 and M_2 .
- $CL(S)$ gives an confidence level how the character path set S can capture the delay character of M .
- **Theroem1:** $CL(S) \geq CL(S_1) * CL(S_2)$

An interesting phenomena

- $P1 \in M1, P1' \in M1,$
- $P \in M2, d$ represent the delay of P
- $f(d) = \text{prob}(d_{P1} + d < \text{clk} \mid d_{P1'} + d < \text{clk})$
- $f(d)$ is almost monotonically decreases with d .



Useful results

$$CL(S_1) = \text{Min}\{\text{prob}(d_{P_1} + d_{P_2} < clk \mid d_{S_1} + d_{P_2} < clk) \mid P_1 \in R_{M_1}, P_2 \in R_{M_2}\}$$

$$f(d) = \text{prob}(d_{P_1} + d < clk \mid d_{P_1'} + d < clk) \mid P_1 \in R_{M_1}, P_1' \in R_{M_1}, P \in R_{M_2}$$

- *If $P_1' = S_1$, then $CL(S_1) = \text{Min}(f(d_{P_2}))$.*
- *$\text{Min}(f(d_{P_2})) = f(d_{M_2})$,*
 - *because $f(d)$ is a monotonically decreasing function,*
 - *where d_{M_2} is the maximum delay of M_2 .*

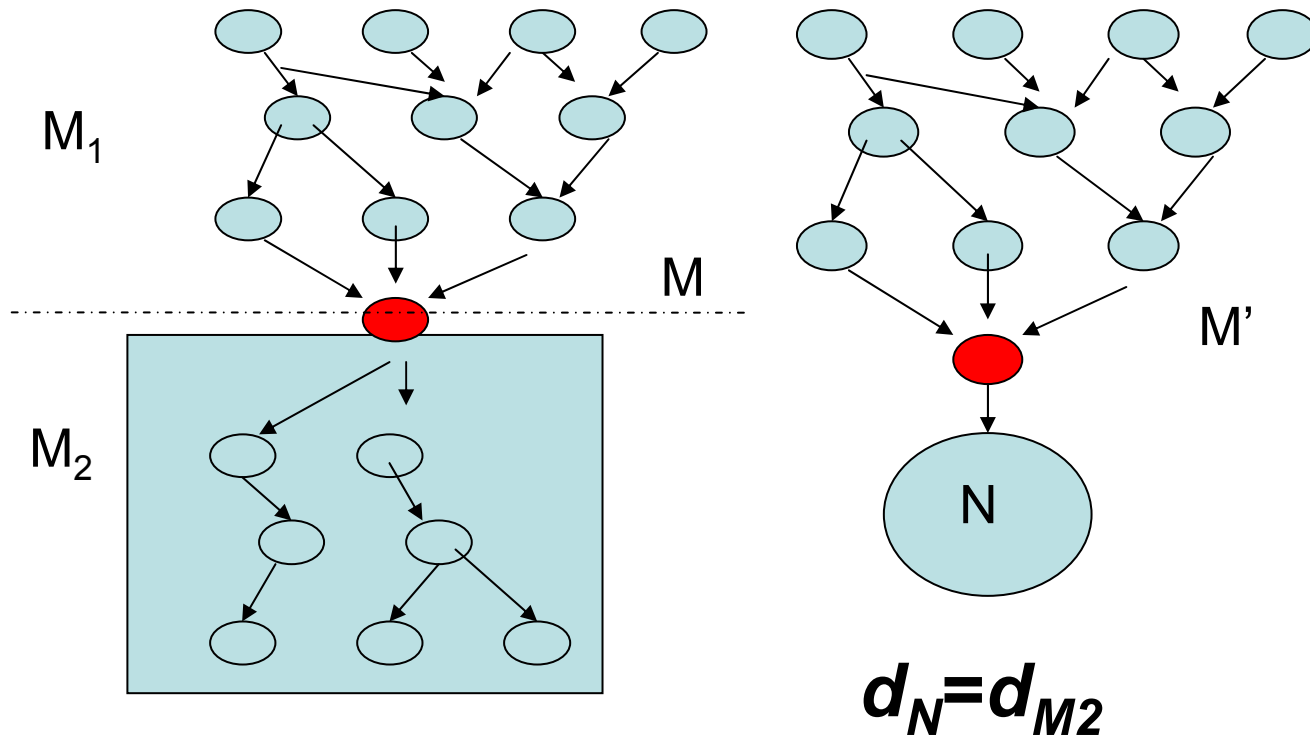
■ Hence

$$CL(S_1) = \text{Min}\{\text{prob}(d_{P_1} + d_{M_2} < clk \mid d_{S_1} + d_{M_2} < clk) \mid P_1 \in R_{M_1}\}$$

$$CL(S_2) = \text{Min}\{\text{prob}(d_{M_1} + d_{P_2} < clk \mid d_{M_1} + d_{S_2} < clk) \mid P_2 \in R_{M_2}\}$$

Abstraction

$$CL(S_1) = \text{Min}\{\text{prob}(d_{P_1} + d_{M_2} < clk \mid d_{S_1} + d_{M_2} < clk) \mid P_1 \in R_{M_1}\}$$

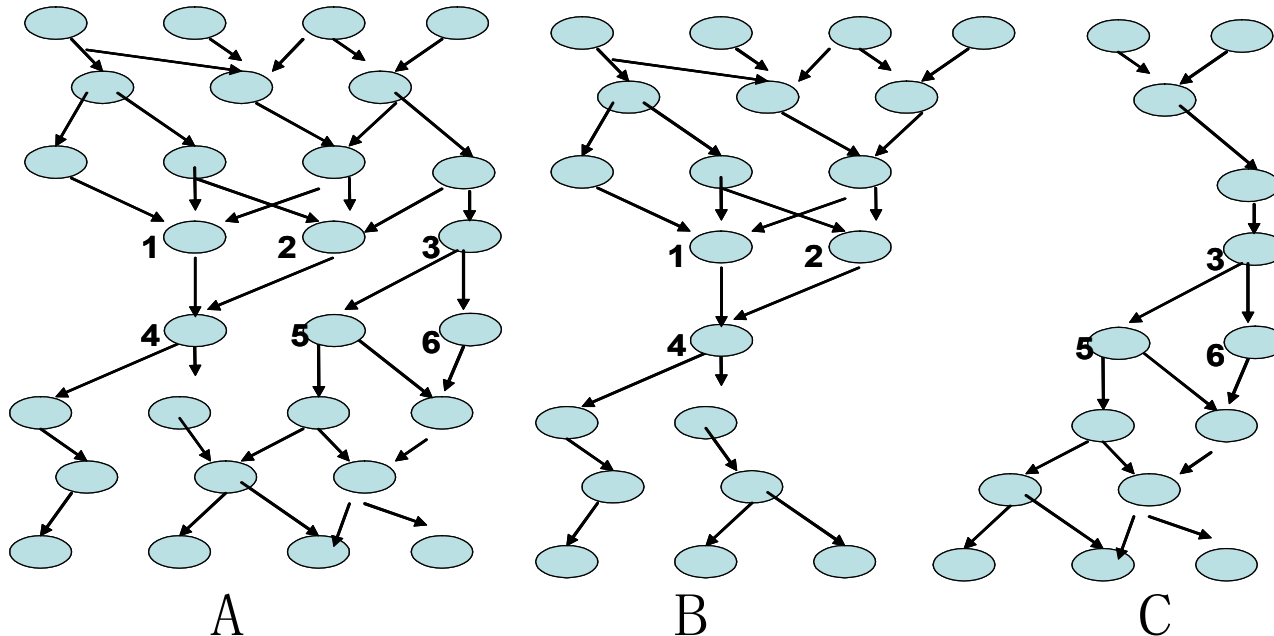


Computation complexity analysis

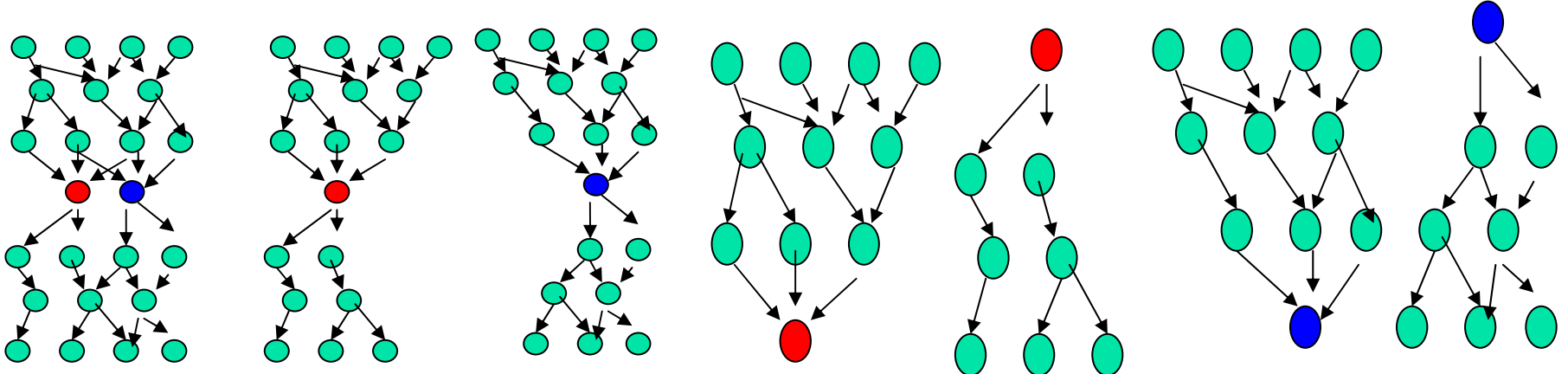
- Graph G is partition into $G1$ and $G2$
 - $M, M1, M2$: path number of $G, G1$ and $G2$
 - $N, N1, N2$: the number of test paths of $G, G1$ and $G2$
- $||M|| = ||M1|| * ||M2||$.
- $||N|| = ||N1|| * ||N2||$.
- The computing time is propositional to $||M||$ and $||N||$
 - Square root level computing complexity

Independent Path Set Partition based path selection

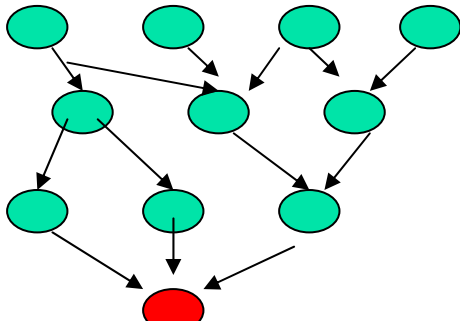
- **CNS** (cut-node set): a node set satisfying the condition that any path of G passes through one and only one node in it.
- The original graph G is partitioned into several sub-graphs G_1, G_2, \dots , each contains a node in CNS
- The test path set of G is the union of the test path set of G_1, G_2, \dots



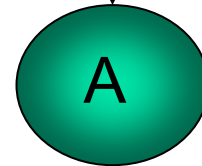
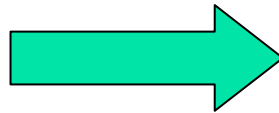
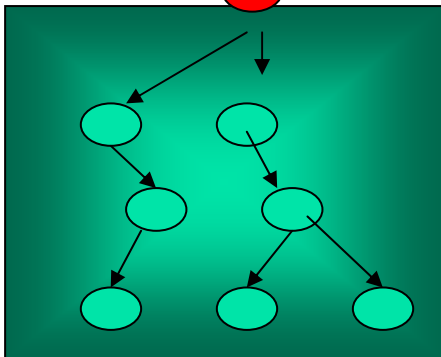
Example



G1



G2



$$d_A = \max\{d_p \mid P \in G2\}$$

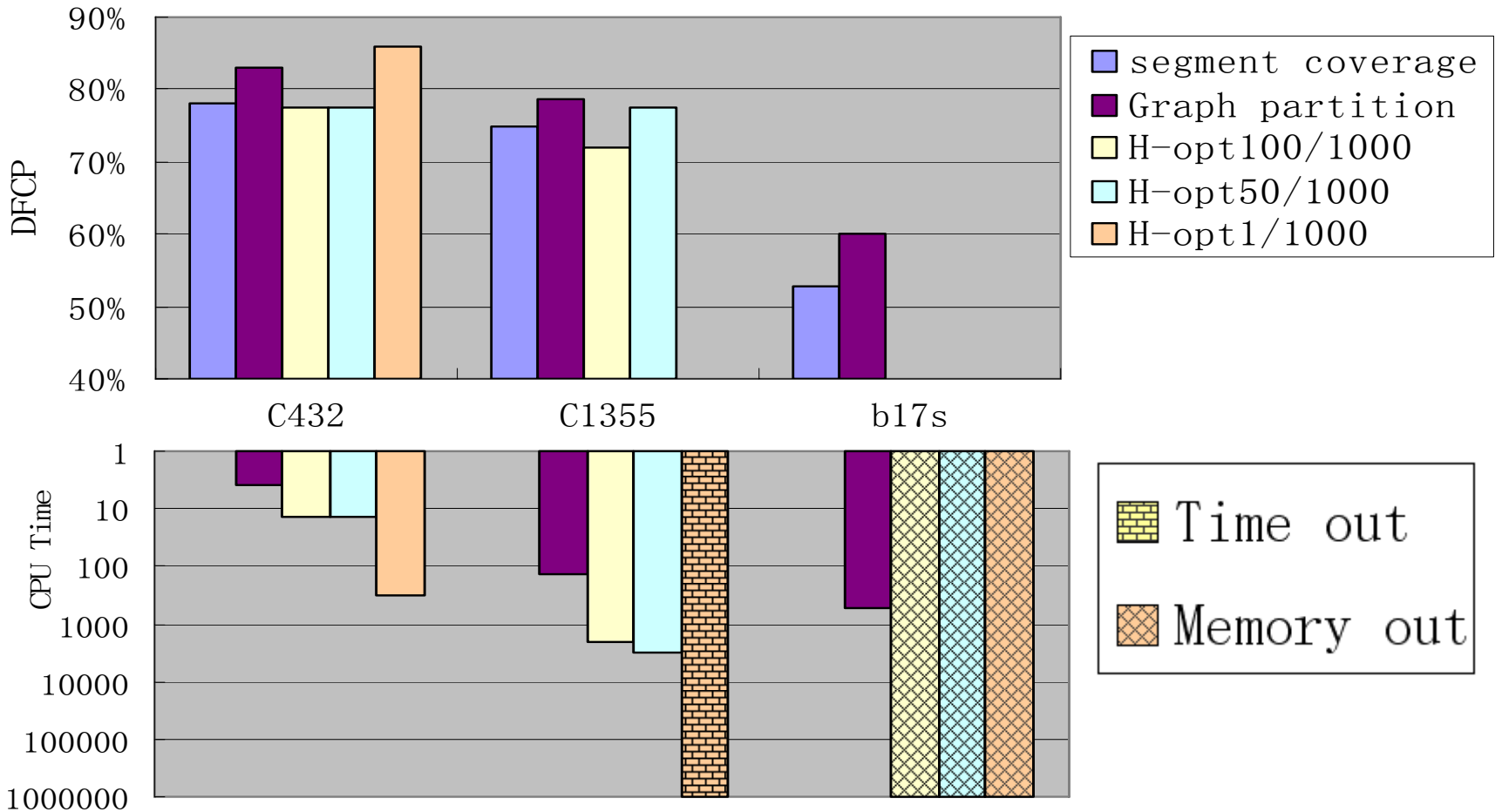
Experimental results(1/2)

- Path selection methods:
 - Segment Coverage
 - H-opt 1/1000, 50/1000, 100/1000*
 - Graph Partition based
- Partial benches

Bench Name	Critical Node Number	Path Number
C432	89	24,786
C1355	426	638,976
b17s	744	133,374,144

* :Critical path selection for delay fault testing based upon a statistical timing model. *IEEE Trans. CAD*

Experimental results(2/2)



C432: 50 paths selected
 C1355: 500 paths selected
 b17s: 500 paths selected

Conclusions & Future work

- Graph-partition base path selection algorithm
 - Cut-node partition based path selection
 - Independent path set partition based path selection
- Advantage
 - Square root level computing complexity
 - Almost the same DFCP compared to MC-based method
- Limitation
 - Can not guaranty the testability of selected paths
- Future work
 - Redundant paths selection for testability

Thank You ! 😊